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(12) United States Design Patent

Chen

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(54) **EMF TESTER**

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(**) Term: **14 Years**

(21) Appl. No.: **29/167,884**

(22) Filed: **Sep. 24, 2002**

(51) **LOC (7) Cl.** **10-04**

(52) **U.S. Cl.** **D10/46**; D10/78

(58) **Field of Search** D10/46, 78; 73/1.84, 73/451; 250/336.1, 366; 324/95, 556, 133; 343/841, 703, 795; 600/559, 549

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(57) **CLAIM**

The ornamental design for a EMF tester, as shown.

DESCRIPTION

FIG. **1** is a perspective view of an EMF tester, showing my new design;

FIG. **2** is a front elevational view thereof;

FIG. **3** is a rear elevational view thereof;

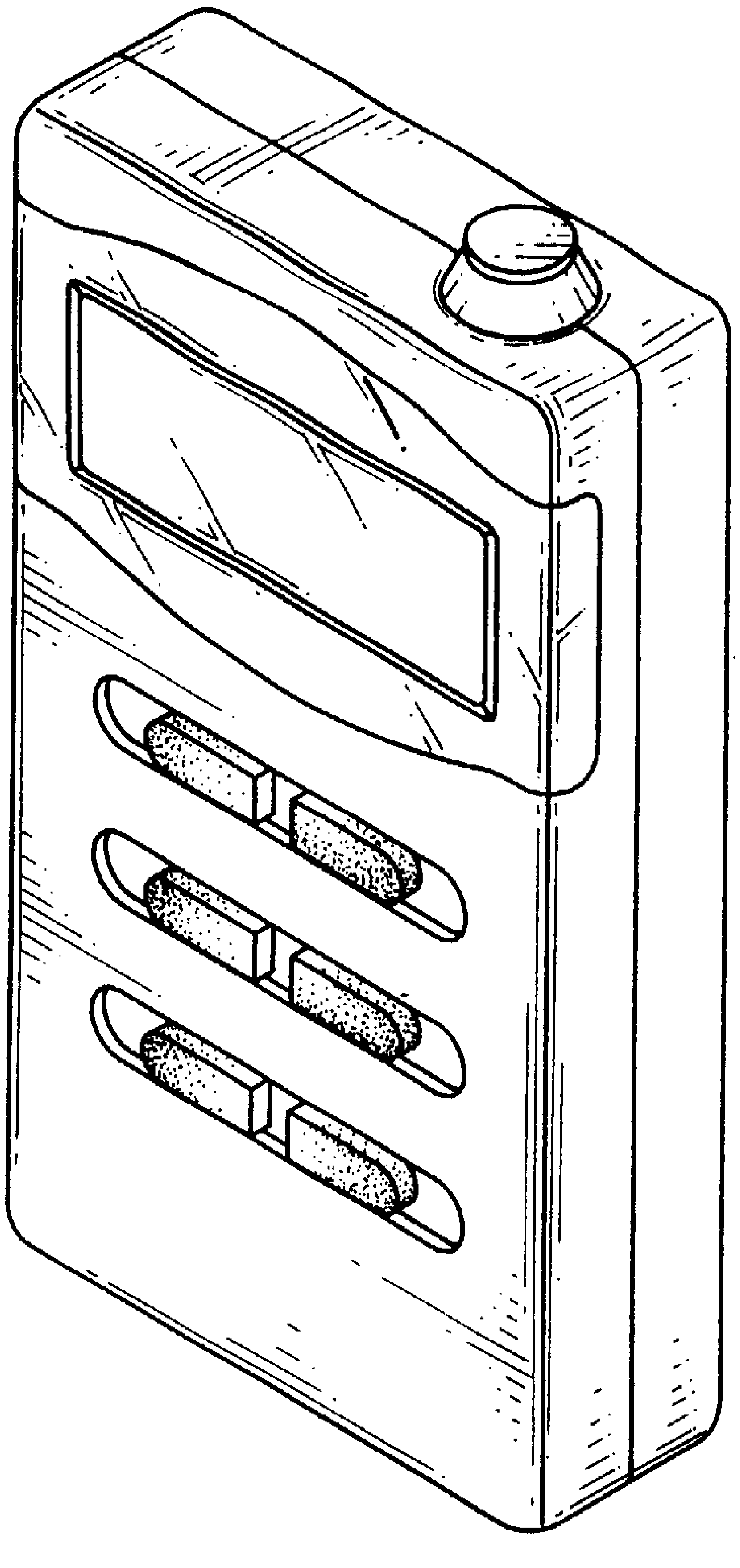
FIG. **4** is a left elevational view thereof;

FIG. **5** is a right elevational view thereof;

FIG. **6** is top plan view thereof; and,

FIG. **7** is a bottom plan view thereof.

1 Claim, 3 Drawing Sheets



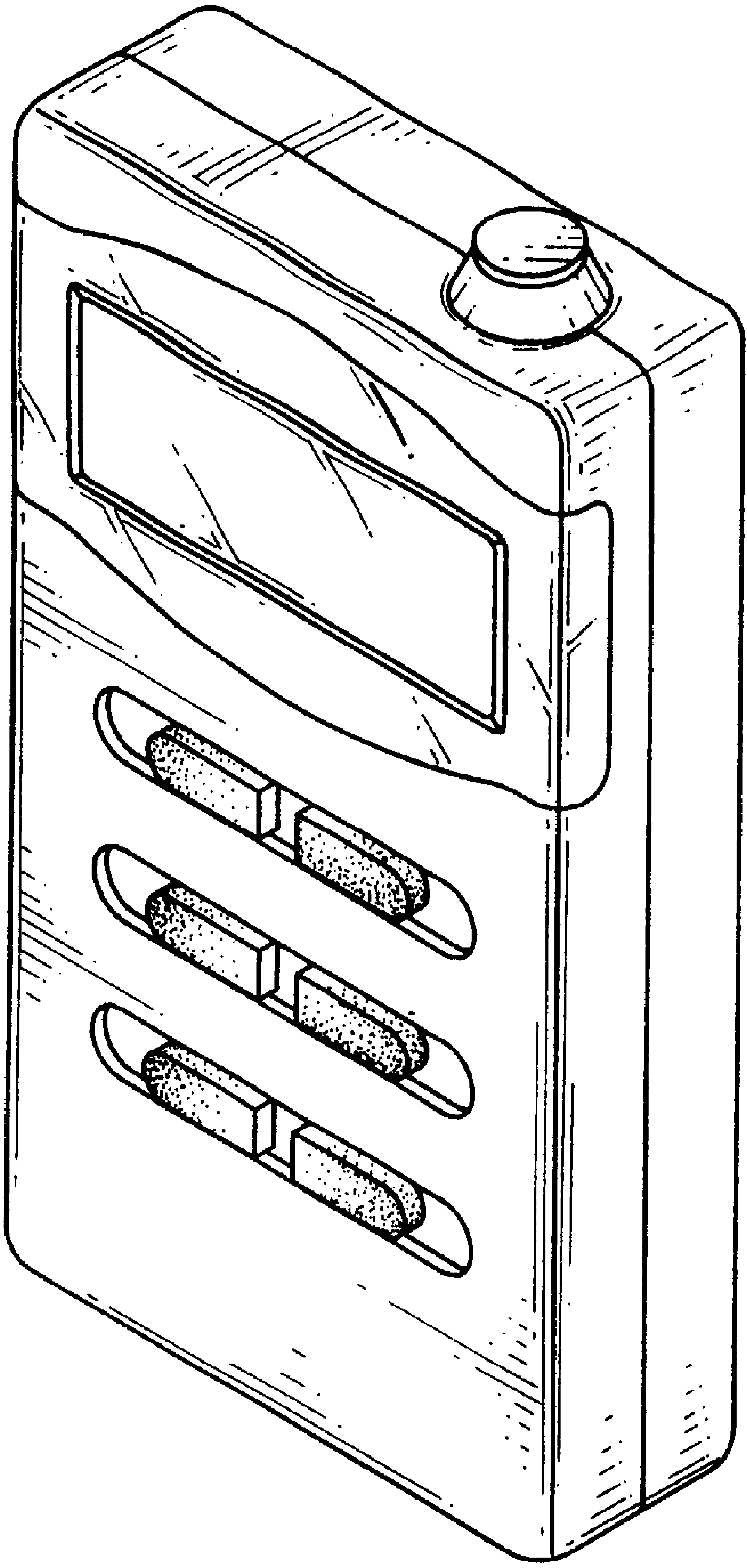


FIG.1

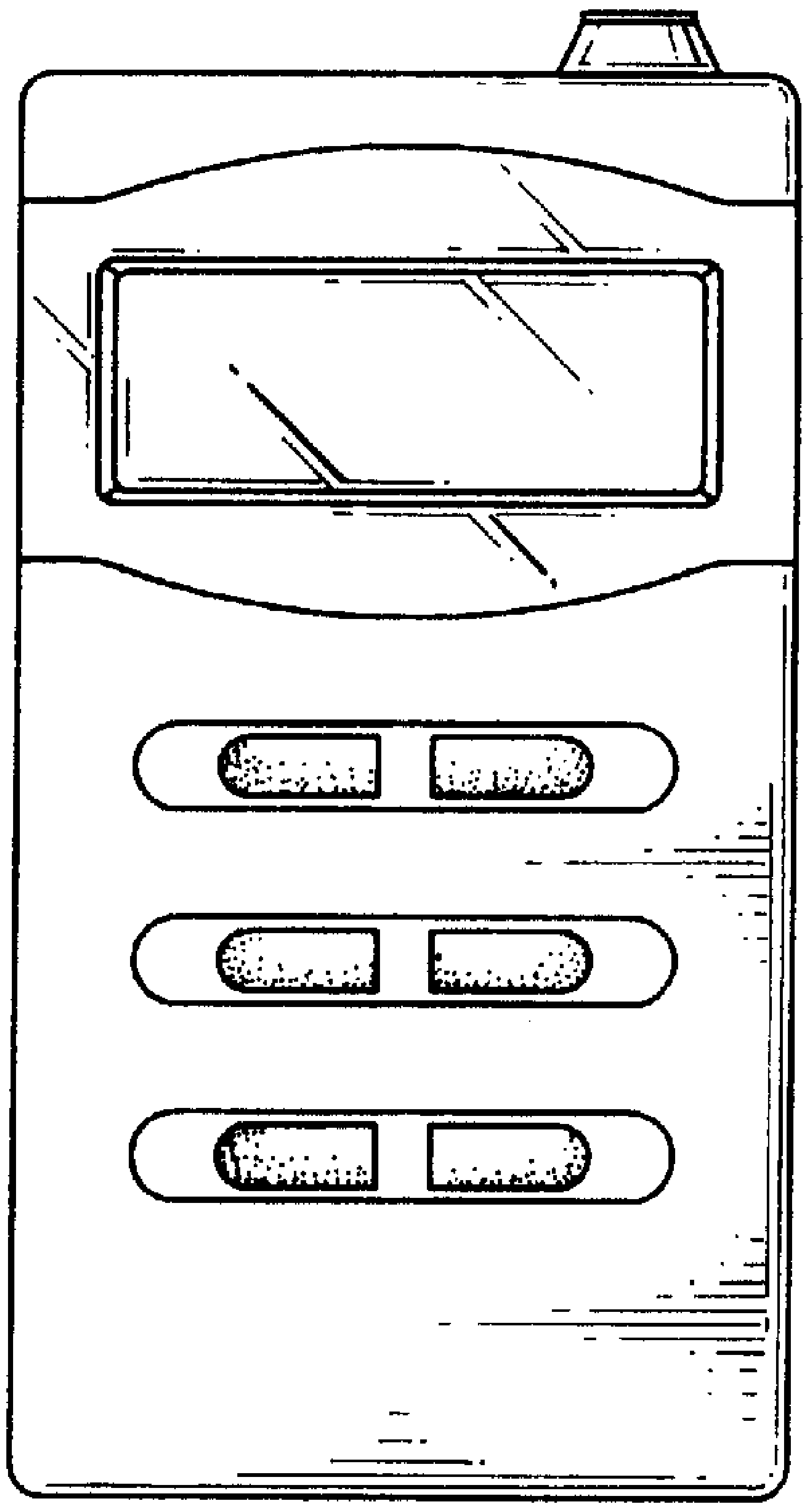


FIG.2

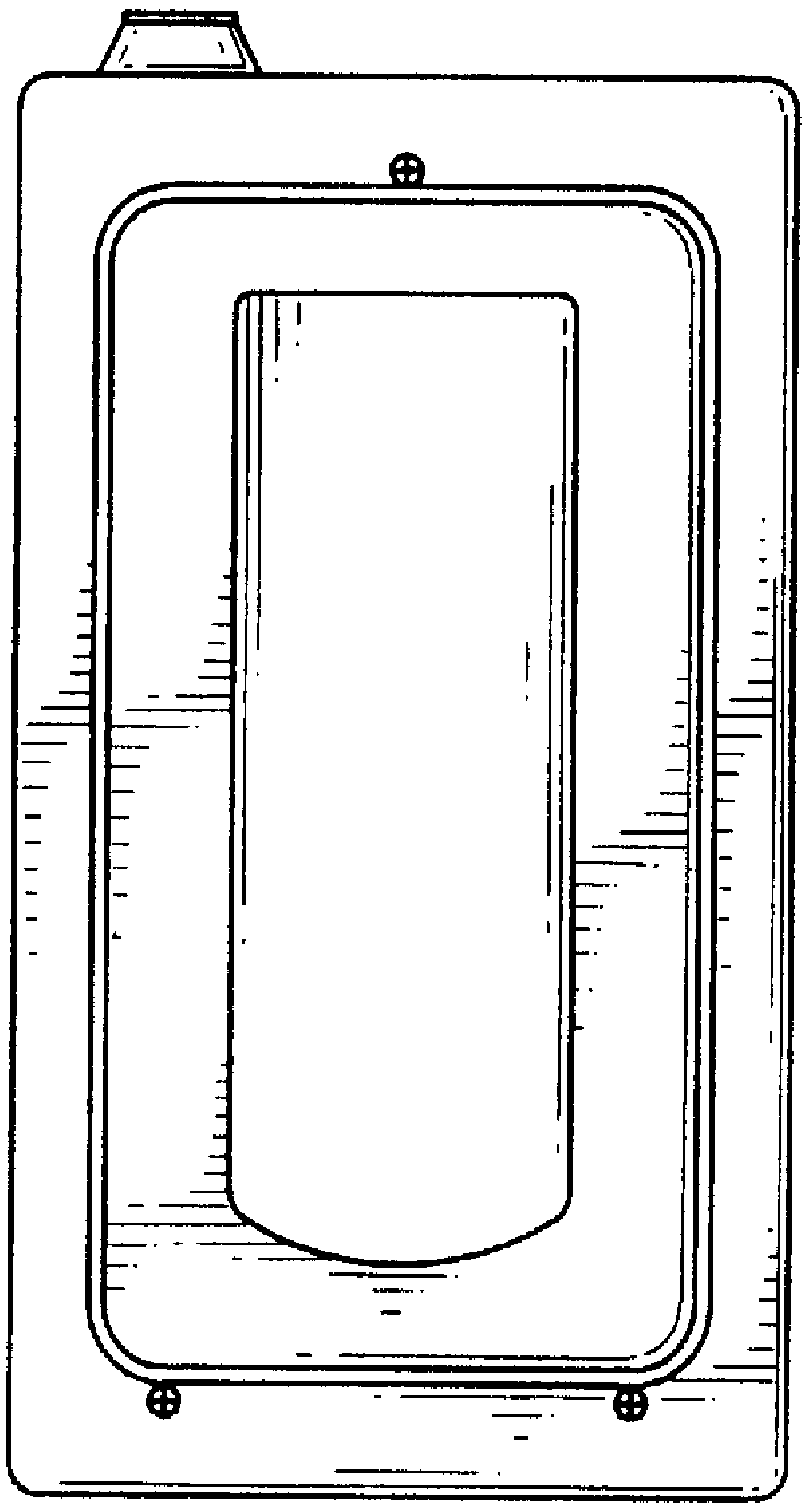


FIG.3

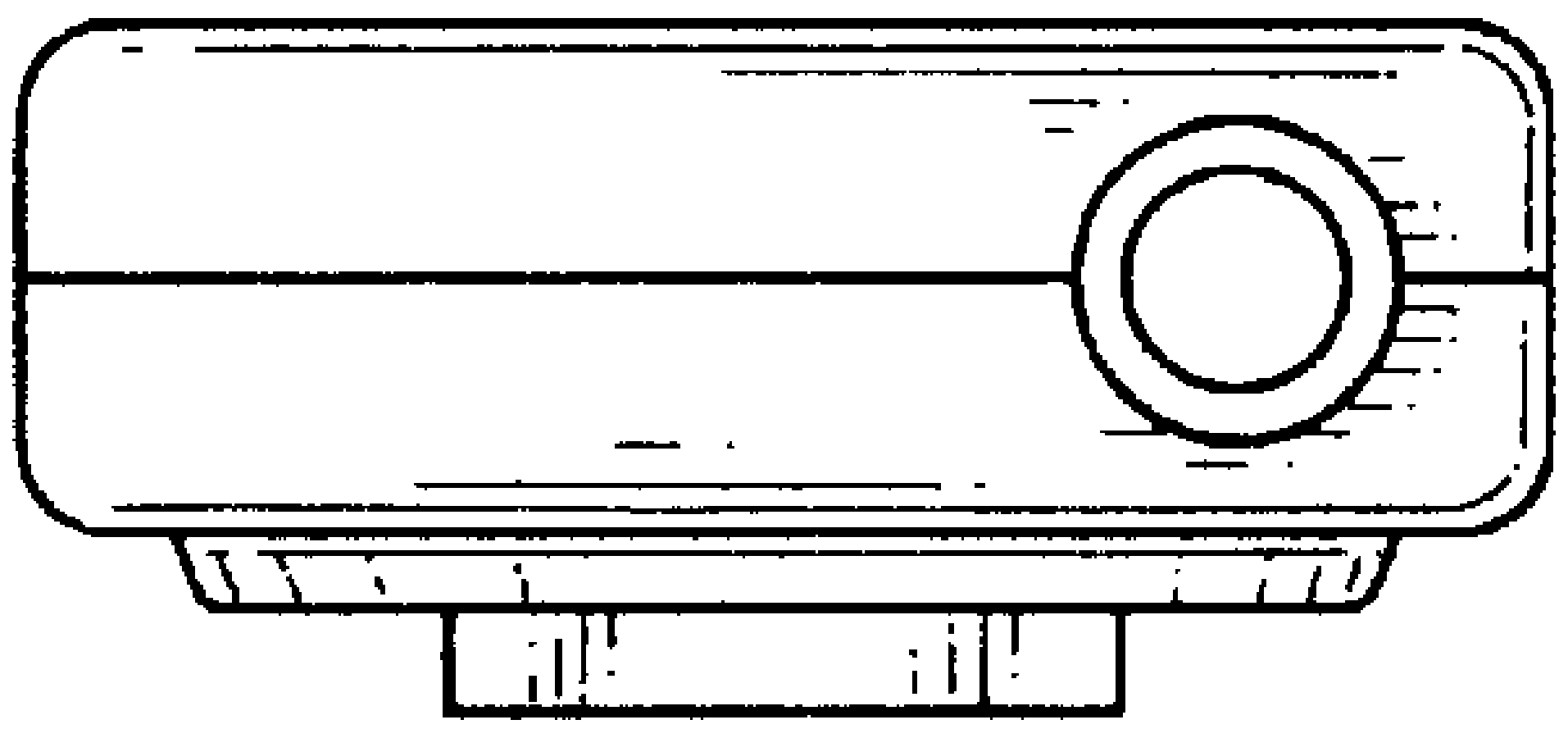


FIG.6

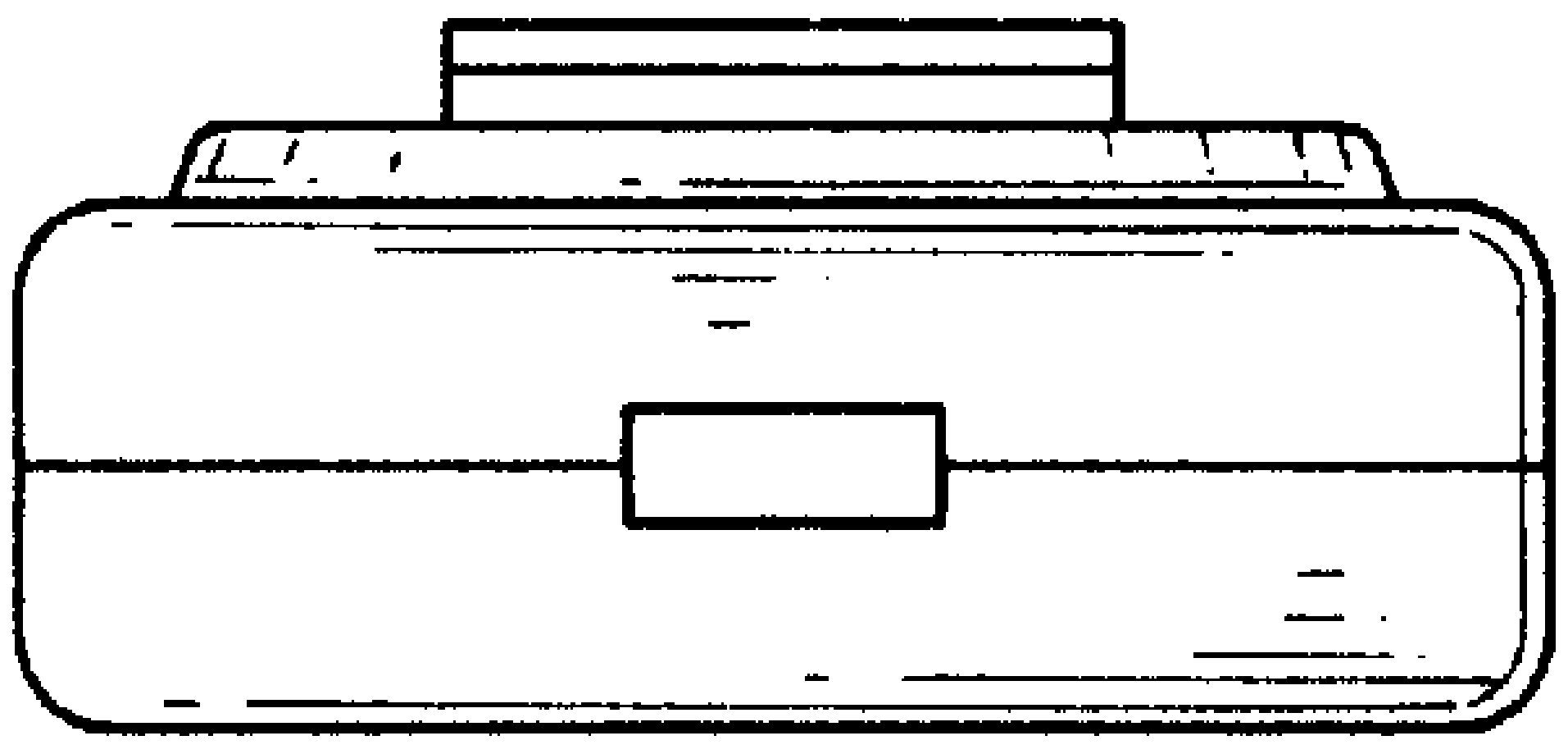


FIG.7

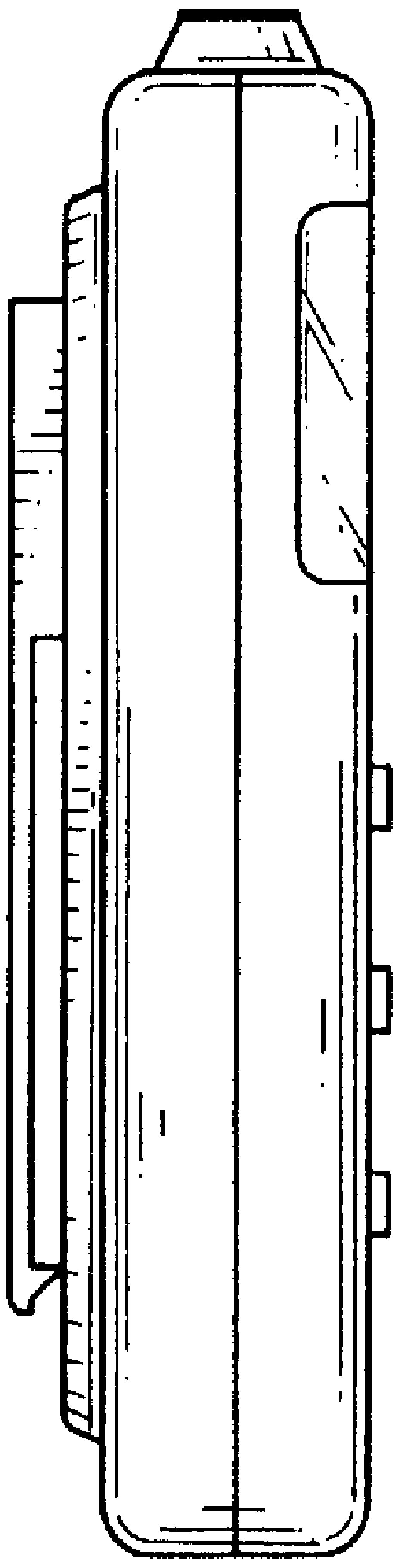


FIG.4

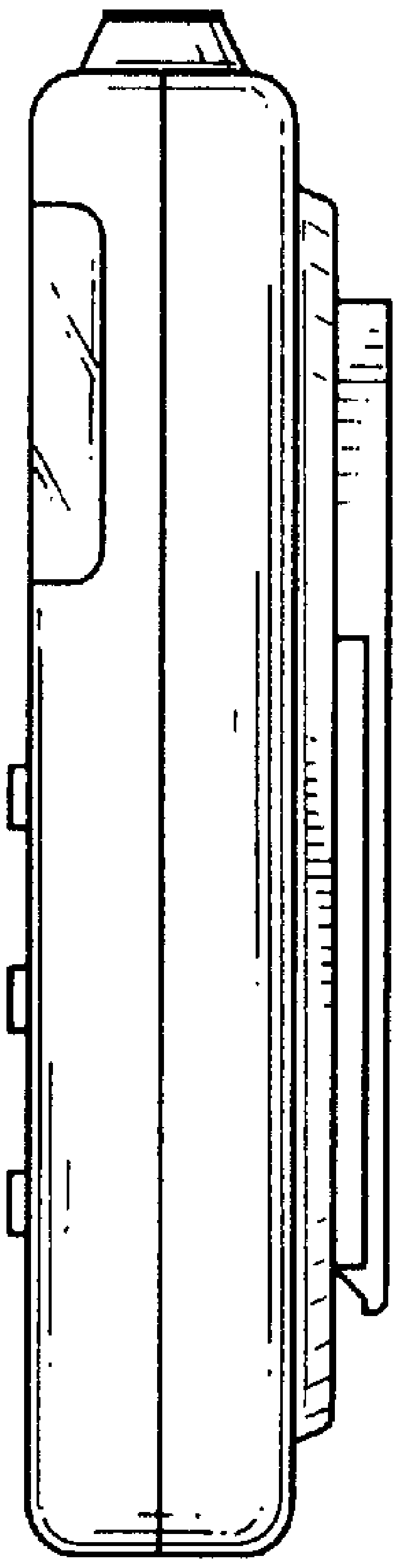


FIG.5